TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

T6B08

ROW DRIVER FOR A DOT MATRIX LCD

The T6B08 is a 68-channel-output row driver for an STN dot matrix LCD. The T6B08 features a -28-V LCD drive voltage. The T6B08 is able to drive LCD panels with a duty ratio of up to 1/240. It is recommended for use with the T6B07.

: 68

: 1-bit bidirectional ① 068←01 ② 068→01

3.0 to 5.5V

– 20 to 75°C

③ 01→034, 068→035

: -11 to -28V (max -30V)

FEATURES

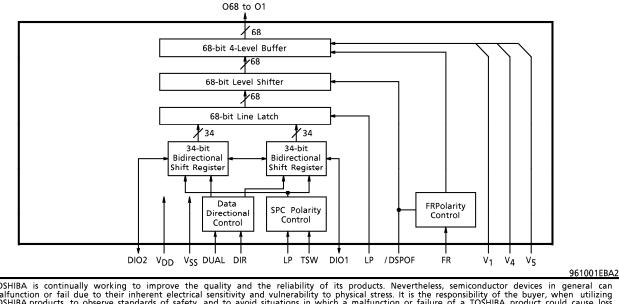
- Display duty application : to 1/240
- LCD drive signal
- Data transfer
- LCD drive voltage
- Operating voltage
- Operating temperature
- LCD drive output resistance : $1.2k\Omega$ (max) (12.8V, 1/9 bias)
- Display-off function
- LCD drive output timing

QFP92-P-1818-0.70B

Weight : 1.45g (typ.)

: When /DSPOF is L, all LCD drive outputs (O1 to O68) remain at the VDD level. : Change on falling edge of LP

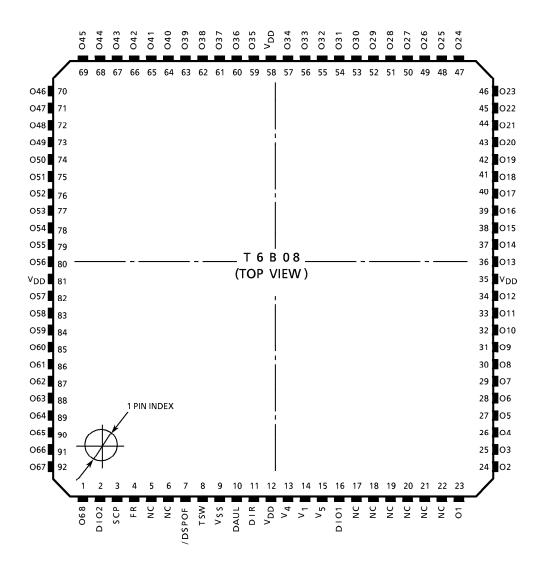
BLOCK DIAGRAM



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PIN ASSIGNMENT



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PIN FUNCTIONS

PIN NAME	1/0	FUNCTIONS	LEVEL	
O1 to O68	Output	Output for LCD drive signal	V _{DD} to V ₅	
DIO1, DIO2	1/0	Input/output for shift data		
LP	Input	(Shift Clock Pulse) Input for shift clock pulse		
FR	Input	(Frame) Input for frame signal		
DUAL	Input	(Dual Mode) Terminal for dual input mode or single input mode select	V _{DD} to	
DIR Input		(Direction) Input for data flow direction select	V _{SS}	
TSW	Input	(Terminal Switch) When tied to V _{SS} : (O1 to O68) output on the rising edge of LP When tied to V _{DD} : (O1 to O68) output on the falling edge of LP		
/ DSPOF	Input	(Display Off) /DSPOF = L: Display-off mode, (O1 to O68) remain at the V _{DD} level. /DSPOF = H: Display-on mode, (O1 to O68) are operational.		
V _{DD}	_	Power supply for internal logic (5V)		
V _{SS}	_	Power supply for internal logic (0V)		
V ₁	—	Power supply for LCD drive circuit		
V4	V ₄ — Power supply for LCD drive circuit			
V5	—	Power supply for LCD drive circuit		

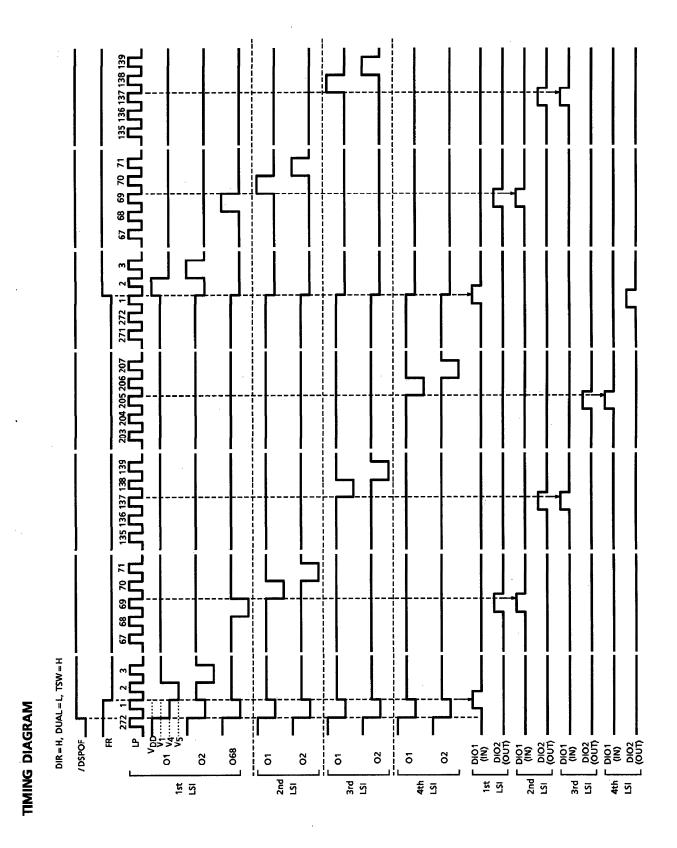
RELATION BETWEEN FR, DATA INPUT AND OUTPUT LEVEL

FR	DATA INPUT (DIO1, DIO2)	/DSPOF	OUTPUT LEVEL
L	L	Н	V ₁
L	Н	Н	V5
Н	L	Н	V ₄
Н	Н	Н	V _{DD}
*	*	L	V _{DD}

* Don't Care

DATA INPUT FORMAT

DUAL	DIR	DATA FLOW	DATA INPUT			
DUAL	DIK	DATATION	DIO1	DIO2		
		01→034	IN	IN		
V _{DD}	V _{DD}	O68→O35	IIN	IIN		
V _{SS}	V _{DD}	O1→O68	IN	OUT		
V _{DD}	V _{SS}	O68→O1	OUT	IN		
V _{SS}	V _{SS}	000	001	IIN		



ABSOLUTE MAXIMUM RATINGS

(Ensure that the following conditions are maintained, $V_{DD} \ge V_1 \ge V_4 \ge V_5$, $V_{SS} = 0$)

ITEM	SYMBOL	PIN NAME	RATING	UNIT
Supply Voltage 1	V _{DD}	V _{DD}	-0.3 to 7.0	V
Supply Voltage 2	V ₁ V ₄ V5	V ₁ V ₄ V5	V _{DD} – 30.0 to V _{DD} + 0.3	V
Input Voltage	VIN	(*1)	-0.3 to V _{DD} +0.3	V
Operating Temperature	T _{opr}	—	– 20 to 75	°C
Storage Temperature	T _{stg}	—	– 55 to 125	°C

(*1) LP, FR, / DSPOF, TSW, DUAL, DIR, DIO1, DIO2

ELECTRICAL CHARACTERISTICS

DC CHARACTERISTICS

TEST CONDITIONS (1) (Unless otherwise noted,

 $V_{SS} = 0V, V_{DD} = 4.5 \text{ to } 5.5V,$ $V_5 = (V_{DD} - 28) \text{ to } (V_{DD} - 11) V, Ta = -20 \text{ to } 75^{\circ}C$

		,		•5 = (•DD	20, 10				20 10 75 C/	
ITEM		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT	PIN NAME	
Supply Volt	age 1	—	—	_	4.5	5.0	5.5	V	V _{DD}	
Supply Volt	age 2	_		_	V _{DD} - 28	_	V _{DD} - 11	V	V ₅	
Input	H Level	VIH		_		_	V _{DD}	V	LP, FR, / DSPOF, TSW,	
Voltage	L Level	VIL	-	—	0	_	0.8	V	DUAL, DIR, DIO1, DIO2	
Output H Level		VOH	_	I _{OH} = -0.5mA		—	V _{DD}	v	DIO1, DIO2	
Voltage	L Level	VOL		IOL=0.5mA	0	—	0.5			
	H Level	ROH		$V_{OUT} = V_{DD} - 0.5V (*2)$		0.65	1.2			
Output	M Level ROM ROM			$V_{OUT} = V_1 \pm 0.5V$ (*2)	_	0.65	1.2	kΩ	O1 to O68	
Resistance				$V_{OUT} = V_4 \pm 0.5V$ (*2)		0.65	1.2	K32		
	L Level	ROL		$V_{OUT} = V_5 + 0.5V$ (*2)		0.65	1.2			
Current Consumption		ISS		$V_{DD} = 5.5V$ $V_{5} = -22.5V$ $f_{FR} = 35.5Hz$ $f_{LP} = 7.1kHz$ $f_{DIO} = 71Hz$ $V_{IH} = 5.5V, V_{IL} = 0V$	_	2.0	4.0	μΑ	V _{SS}	

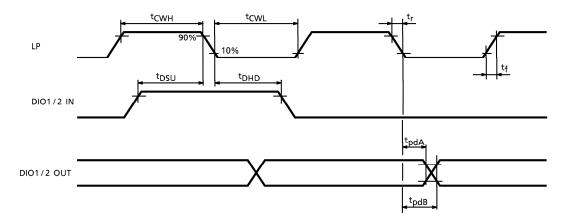
(*2) $V_{DD} = 5.0V, V_5 = -7.8V, V_1 = V_{DD} - 1/9 (V_{DD} - V_5), V_4 = V_{DD} - 8/9 (V_{DD} - V_5)$

TEST CONDI	Contess ou	ierwis	e noted, V _S S = UV, V _{DD} V ₅ = (V _{DD} – 28				= - 20	to 75°C)		
ITEM		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN	TYP.	ΜΑΧ	UNIT	PIN NAME	
Supply Volt	age 1		_	—	3.0	3.3	5.5	V	V _{DD}	
Supply Volt	age 2	—		_	V _{DD} - 28	_	V _{DD} - 11	V	V5	
Input	H Level	VIH		—	V _{DD} -0.6	_	V _{DD}	v	LP, FR, / DSPOF, TSW,	
Voltage	L Level	VIL		_	0	_	0.6	v	DUAL, DIR, DIO1, DIO2	
Output	H Level	VOH	_	I _{OH} = -0.5mA	V _{DD} - 0.5	_	V _{DD}	v	DIO1, DIO2	
Voltage	L Level	VOL		loL = 0.5mA	0	—	0.5			
	H Level	ROH		$V_{OUT} = V_{DD} - 0.5V (*3)$	—	0.65	1.2		O1 to O68	
Output	M Level	ROM		$V_{OUT} = V_1 \pm 0.5V$ (*3)	—	0.65	1.2	kΩ		
Resistance		Rom		$V_{OUT} = V_4 \pm 0.5V$ (*3)	—	0.65	1.2	K77	01 10 008	
	L Level	ROL		$V_{OUT} = V_5 + 0.5V$ (*3)	—	0.65	1.2			
Current Consumption		ISS		$V_{DD} = 5.5V$ $V_{5} = -22.5V$ $f_{FR} = 35.5Hz$ $f_{LP} = 7.1kHz$ $f_{DIO} = 71Hz$ $V_{IH} = 5.5V, V_{IL} = 0V$		2.0	4.0	μΑ	Vss	

TEST CONDITIONS (2) (Unless otherwise noted, $V_{SS} = 0V$, $V_{DD} = 3.0$ to 5.5V,

(*3) $V_{DD} = 3.0V, V_5 = -9.8V, V_1 = V_{DD} - 1/9 (V_{DD} - V_5), V_4 = V_{DD} - 8/9 (V_{DD} - V_5)$

AC CHARACTERISTICS



TEST CONDITIONS (1) ($V_{SS} = 0V$, $V_{DD} = 4.5$ to 5.5V, $V_5 = (V_{DD}-28)$ to ($V_{DD}-11$) V, Ta = -20 to 75°C)

ITEM	SYMBOL	TEST CONDITION	MIN	MAX	UNIT
SCP Pulse Width H	^t CWH	LP	40	_	ns
SCP Pulse Width L	tcwl	LP	1	—	μ s
Input Rise/Fall Time	t _r , t _f	LP, FR, DIO1, DIO2	—	(*6)	ns
Data Set-up Time	tDSU	DIO1, DIO2	40	—	ns
Data Hold Time	^t DHD	DIO1, DIO2	40	—	ns
Output Data Delay Time A (*5)	tpdA	DIO1, DIO2	500	_	ns
Output Data Delay Time B (*5)	tpdB	DIO1, DIO2	—	1	μs

TEST CONDITIONS (2) (V	$V_{SS} = 0V, V_{DD} = 3.0$ to !	5.5V, $V_5 = (V_{OO} - 28)$ to	$(V_{DD}-11) V$, Ta = -20 to $75^{\circ}C$)
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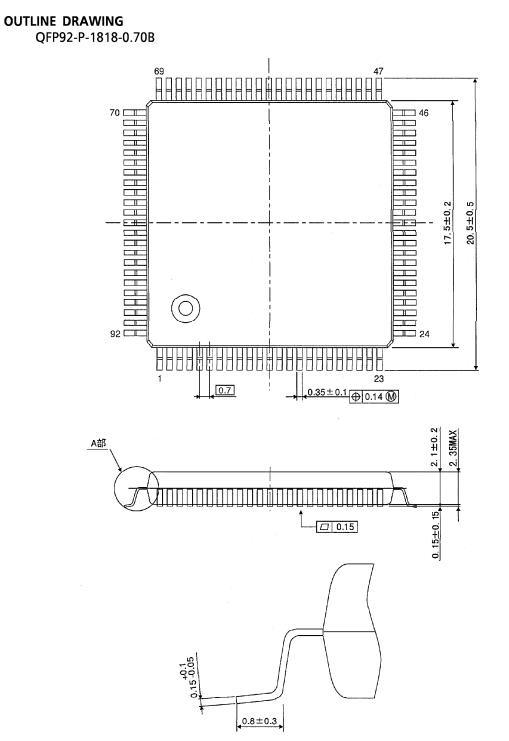
ITEM	SYMBOL	TEST CONDITION	MIN	MAX	UNIT
SCP Pulse Width H	tcwh	LP	50	—	ns
SCP Pulse Width L	tcwl	LP	1	—	μ s
Input Rise/Fall Time	t _r , t _f	LP, FR, DIO1, DIO2	_	(*6)	ns
Data Set-up Time	tDSU	DIO1, DIO2	50	—	ns
Data Hold Time	tDHD	DIO1, DIO2	50	—	ns
Output Data Delay Time A (*5)	tpdA	DIO1, DIO2	700	_	ns
Output Data Delay Time B (*5)	tpdB	DIO1, DIO2	_	1	μs

(*5) $C_L = 10 pF$

(*6) $t_r, t_f \leq (t_C - t_{CWH} - t_{CWL}) / 2$ or $t_r, t_f \leq 50$ ns

NOTE

Insert the bypass capacitor (0.1 μ F) between V_{DD} and V_{SS} to decrease the power supply noise. Place the bypass capacitor as close to the LSI as possible.



Unit : mm

Weight : 1.45g (Typ.)